



GreenFET3 SLG59M1742C Layout Guide

Content

- 1. Description
- 2. Power and Ground Planes
- 3. Basic Test Setup and Connections

Description

The SLG59M1742C is a 18 m Ω , ~1 A single-channel load switch that is able to switch 0.25 V to 1.5 V power rails. The product is packaged in an ultra-small 0.71 x 1.16 mm package.

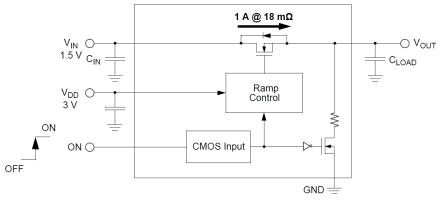


Figure 1: SLG59M1742C Block Diagram

This layout guide provides some important information about the PCB layout of SLG59M1742C applications.

<section-header>SIEGO WLCSP 0.71x1.16-6B PKG Unit: µm

Solder mask detail (not to scale) Figure 2. SLG59M1742C Package Dimensions and

Recommended Land Pattern

- 2. Power and Ground Planes
- 2.1.The VDD pin (B2) needs a 0.1µF (or larger) external capacitor to smooth pulses from the power supply.Locate this capacitor as close to B2 pin.
- 2.2. The trace length from the control IC to the ON pin should be as short as possible and must avoid crossing this trace with power rails.
- 2.3. The VIN and VOUT pins carry significant current. Please note how the VIN and VOUT pads are placed directly on the power planes in Figure 3, which minimizes the RDS_{ON} associated with long, narrow traces. The VIN, VOUT and GND pins dissipate most of the heat generated during highload current condition. The layout shown in Figure 3 is illustrating a proper solution for heat to transfer as efficiently as possible out of the device.
- 2.4. Connect a 1 μ F (or larger) low-ESR capacitor from VIN pin (A2) to ground.
- 2.5. The GND pin (C1) should be connected to GND.

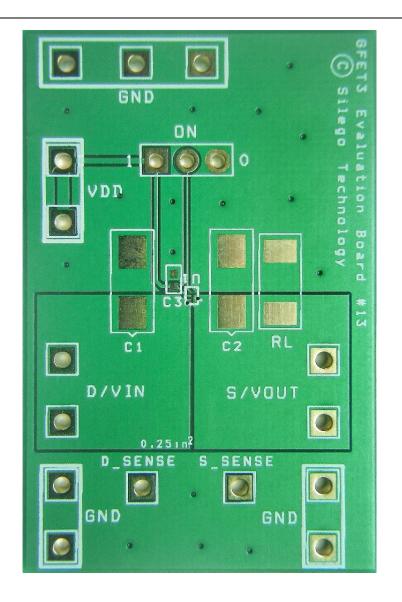
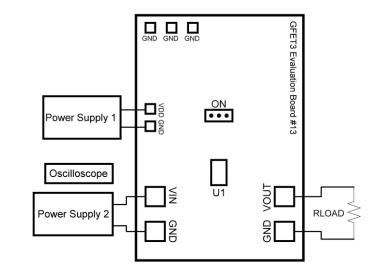


Figure 3. SLG59M1742C Evaluation Test Board

Note: Evaluation board has D_Sense and S_Sense pads. Please use them only for $\mbox{RDS}_{\mbox{ON}}$ evaluation.

3. Basic Test Setup and Connections





3.1 EVB Configuration

- 1. Connect oscilloscope probes to VIN, VOUT, ON, etc.
- 2. Turn ON Power Supply 1 and set desirable V_{DD} in range of 2.7 V…3.6 V
- 3. Turn ON Power Supply 2 and set desirable V_{IN} in range of 0.25 V…1.5 V
- 4. Switch ON to High or Low to evaluate GFET3 operation